Sensor table unique ID type batch # wafer # reticle name vendor processing height, mm width, mm strips per side year owner location V_fd, V I_150V_20C I 250V 20C P-strips defect N-strips defect quality grade (1..10) problem, Y/N QA passed, Y/N opt. check passed, Y/N comment

Geometry unique ID vendor type wafer # reticle name

processing
height, mm
width, mm
pitch, um
stereo angle P/N
strips per side

unique ID type wafer # V_fd, V I_150V_20C I_250V_20C P-strips defect N-strips defect quality grade problem, Y/N QA passed, Y/N optical check passed, Y/N comment

Ownership

unique ID

vendor
type
wafer #
reticle name
year
owner
location

type
wafer #
AC cap OK P-side, Y/N
AC cap OK N-side, Y/N
AC cap value P-side, pF
AC cap value N-side, pF
I_strip P-side, nA
I_strip N-side, nA

Channel map